An aerial photograph of the Jefferson Lab facility, showing various buildings, roads, and green spaces. A red diagonal bar runs from the bottom left towards the top right.

**A-M Valente-Feliciano**

**A. Anders (LBNL)**

**S. Calatroni, G. Terenziani (CERN)**

**A. Eriasarian (Sheffield Hallam Univ.)**

**L. Phillips (JLab)**

# HiPIMS

## A New Generation of Films Deposition Techniques for SRF Applications

Thomas Jefferson National Accelerator Facility is managed by  
Jefferson Science Associates, LLC, for the U.S. Department of Energy's Office of Science



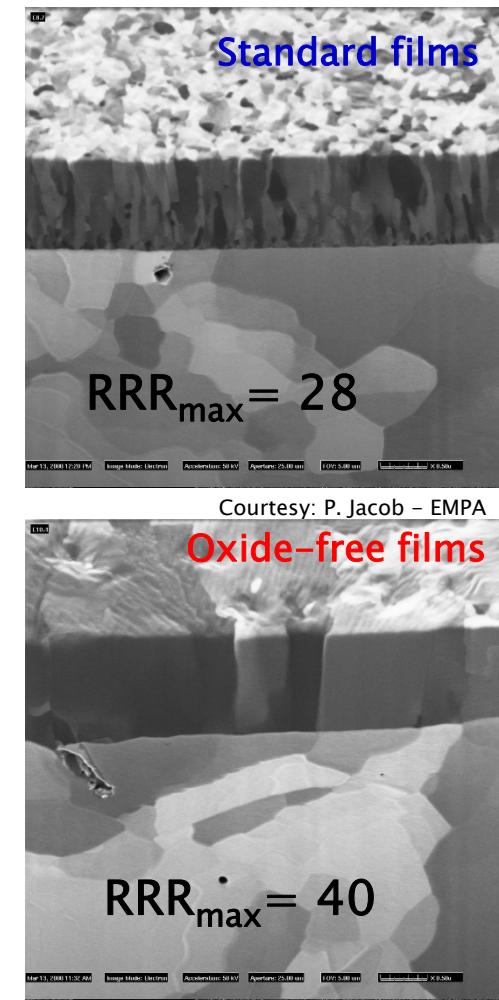
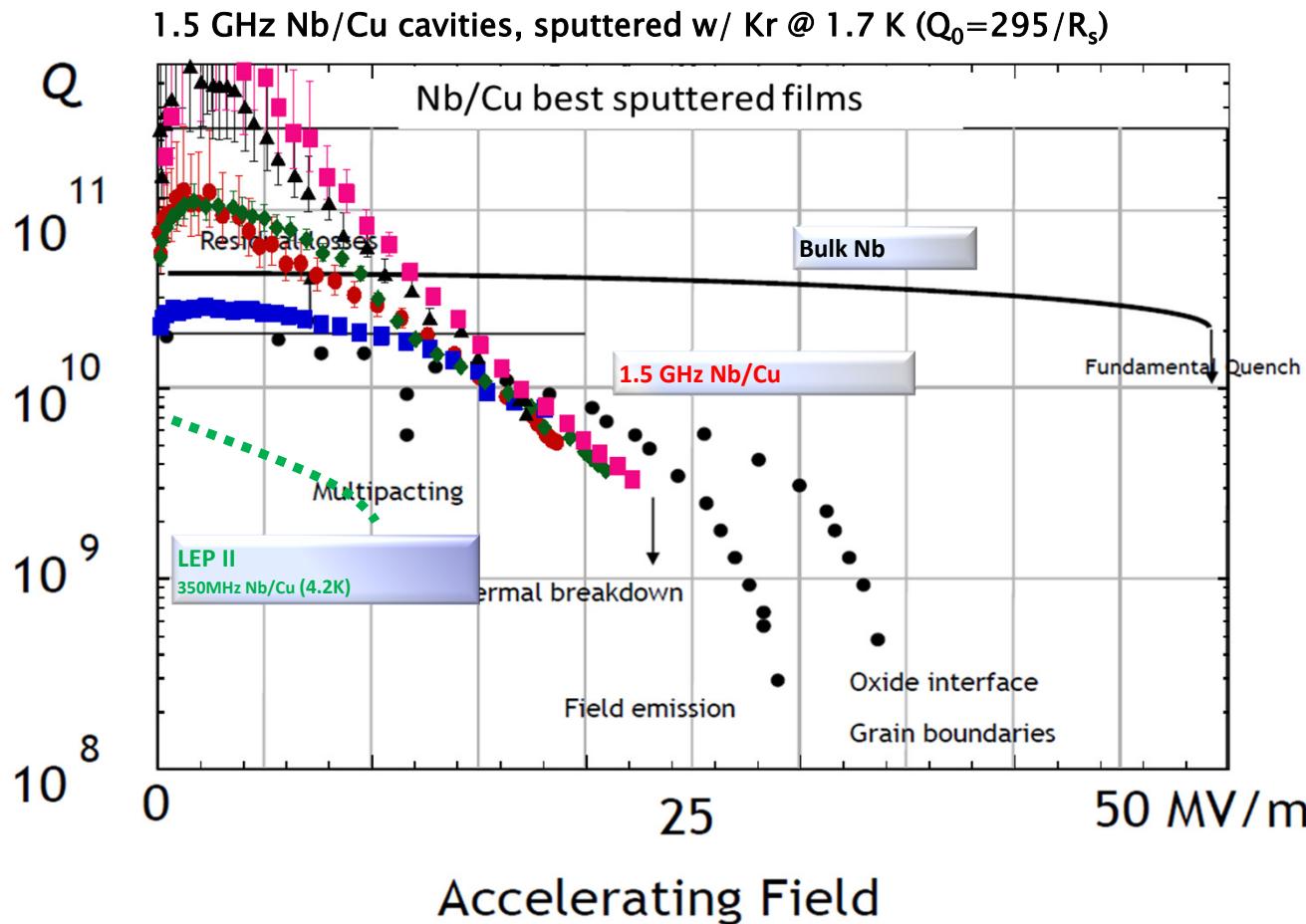
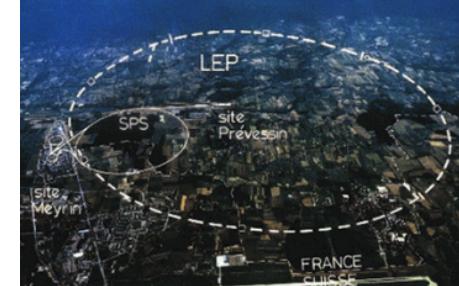
# Outline

- SRF films- State of the Art
- Energetic Condensation
- Energetic Condensation Techniques
- HiPIMS Principle
- HiPIMS: an array of techniques
- Application to SRF Surfaces
- HiPIMS @ LBNL
- HiPIMS @ CERN
- HiPIMS @ JLAB
- Conclusions



# Thin Films for SRF–state of the art

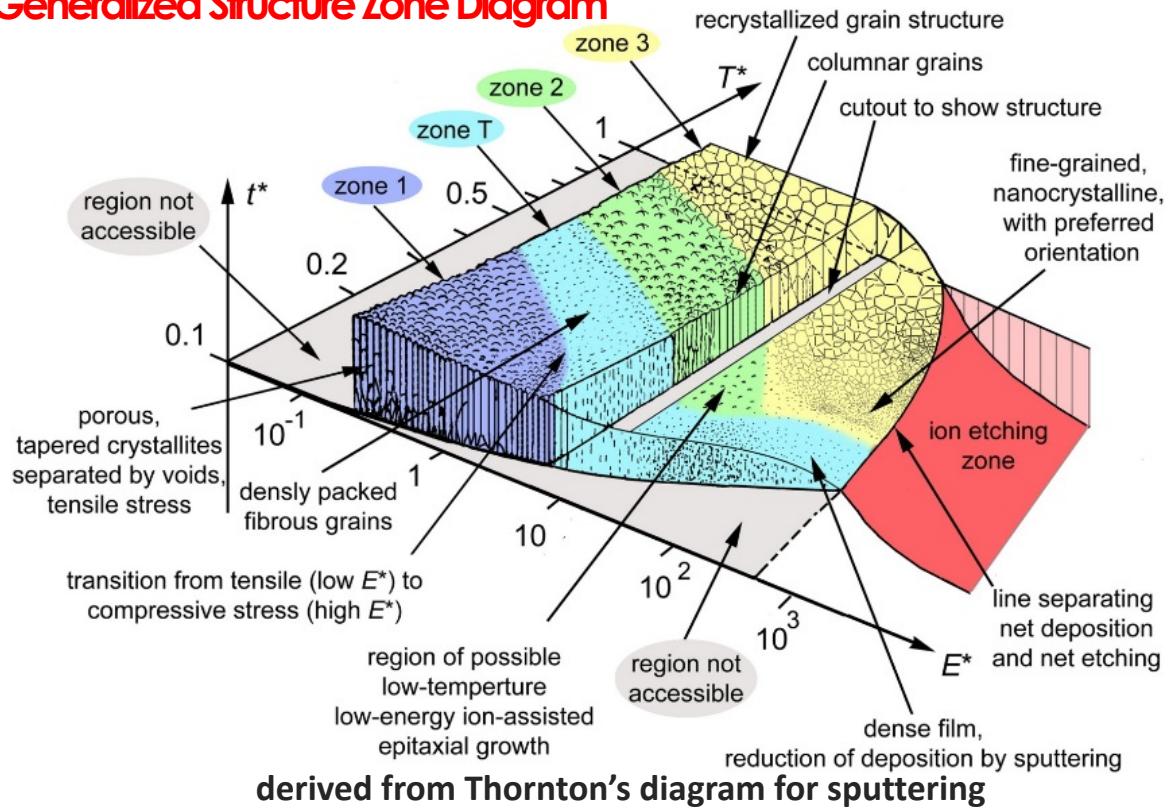
- CERN LEP 2      272 x 353MHz Nb/Cu 4-cell cavities
- INFN Legnaro    52 x 160 MHZ Nb/Cu QWR



# Energetic Condensation

Condensing (film-forming) species : hyper-thermal & low energies ( $> 10$  eV).

## Generalized Structure Zone Diagram



derived from Thornton's diagram for sputtering

(1974)

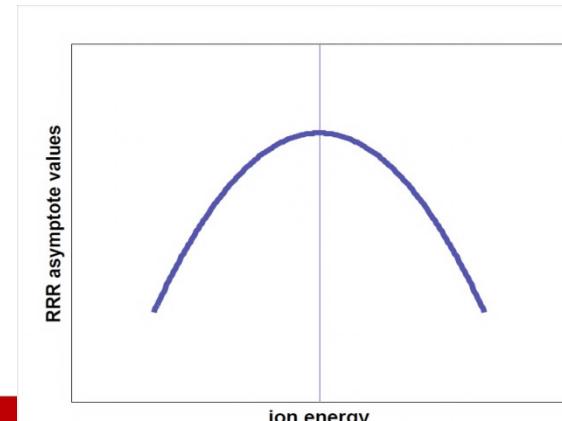
A. Anders, Thin Solid Films 518 (2010) 4087

Additional energy provided by fast particles arriving at a surface  
 ⇒ number of surface & sub-surface processes ⇒ changes in the film growth process:

- residual gases desorbed from the substrate surface
- chemical bonds may be broken and defects created thus affecting nucleation processes & film adhesion
- enhanced mobility of surface atoms
- stopping of arriving ions under the surface

⇒ Changes in

- morphology
- microstructure
- stress



# Energetic Condensation Techniques

*A variety of techniques with distinct technologies*

- High Impulse Power Magnetron sputtering (HiPIMS)
- Vacuum Arc Plasma
- Coaxial Energetic Deposition (CED)
- Electron cyclotron Resonance (ECR)

**WEIOA02 Thin Film Growth by Energetic Condensation**  
**Mahadevan Krishnan - Alameda Applied Sciences Corporation**

# Energetic Condensation Techniques

*A variety of techniques with distinct technologies*

- High Impulse Power Magnetron sputtering (HiPIMS)
- Vacuum Arc Plasma
- Coaxial Energetic Deposition (CED)
- Electron cyclotron Resonance (ECR)

***Engineering for optimum RF performance***

**3 sequential phases for film growth**

- ✓ Film nucleation on the substrate
- ✓ Growth of an appropriate template for subsequent deposition of the final RF surface
- ✓ Deposition of the final surface optimized for minimum defect density.

# HIPIMS: A Form of “Ionized Sputtering”

## *One Approach to Energetic Deposition*

“What distinguishes HIPIMS from the long-practiced pulsed sputtering?”

### **Technical Definition:**

*HIPIMS is pulsed sputtering where the peak power exceeds the average power by typically two orders of magnitude.*

(implies a long pause between pulses, hence the term “impulse”)

### **Physical Definition:**

*HIPIMS is pulsed sputtering where a very significant fraction of the sputtered atoms becomes ionized.*

(implies that self-sputtering occurs, which may or may not be sustained by target ions)

A. Anders, Surf. Coat. Technol. **205** (2011) S1.

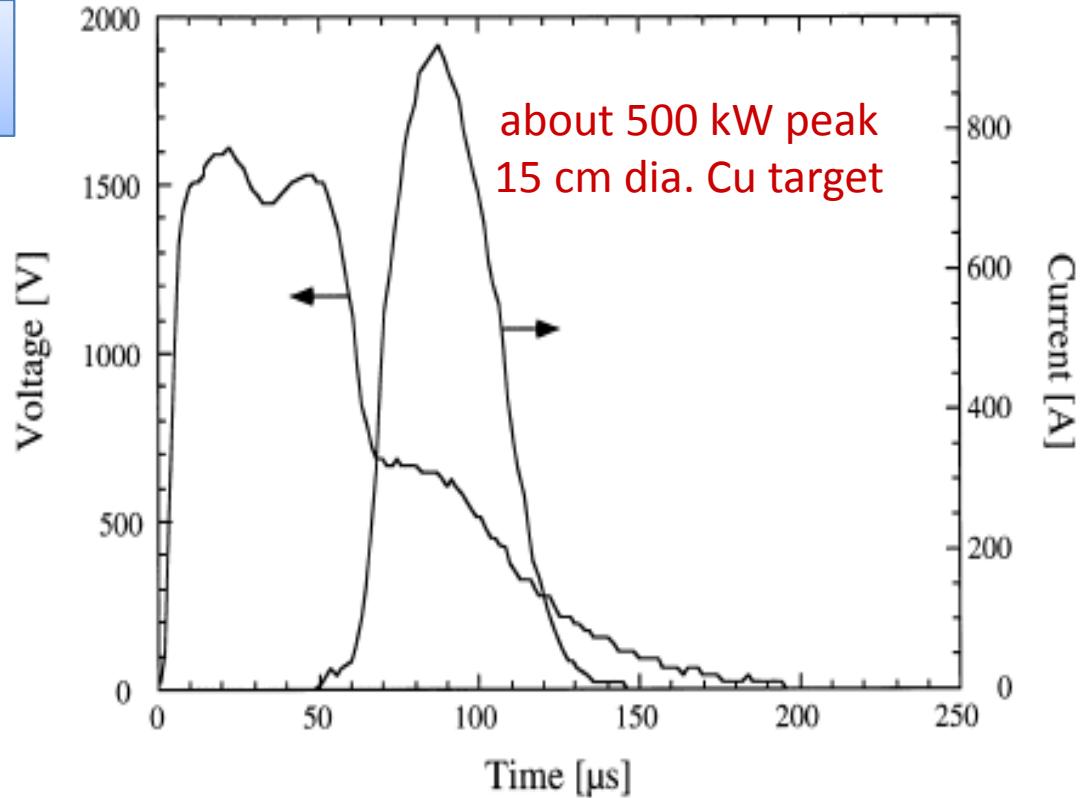


image from the seminal (but not first) paper:  
V. Kouznetsov, *et al.*, Surf. Coat. Technol. **122** (1999) 290

Why do we care? Because bias can be applied to affect film-forming ions (not atoms)!

substrate

ions to substrate

atoms to substrate

A. Anders, Surf. Coat. Technol.  
205 (2011) S1.

Ionization  
probability

Condition of self-  
sputtering  
runaway

$$\Pi \equiv \alpha \beta \gamma > 1$$

Probability for ion  
to return to target

$\beta$

secondary  
electron  
yield  
 $\gamma_{SE}$

$\alpha$

sputter  
yield  
 $\gamma$

Condition of  
steady-state  
self-sputtering

$$\Pi \equiv \alpha \beta \gamma = 1$$

target

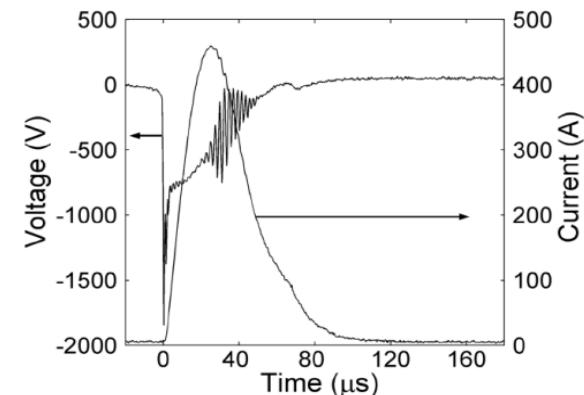
# HiPIMS-High Power Impulse Magnetron Sputtering

*High Impulse Power Magnetron Sputtering (HiPIMS)*

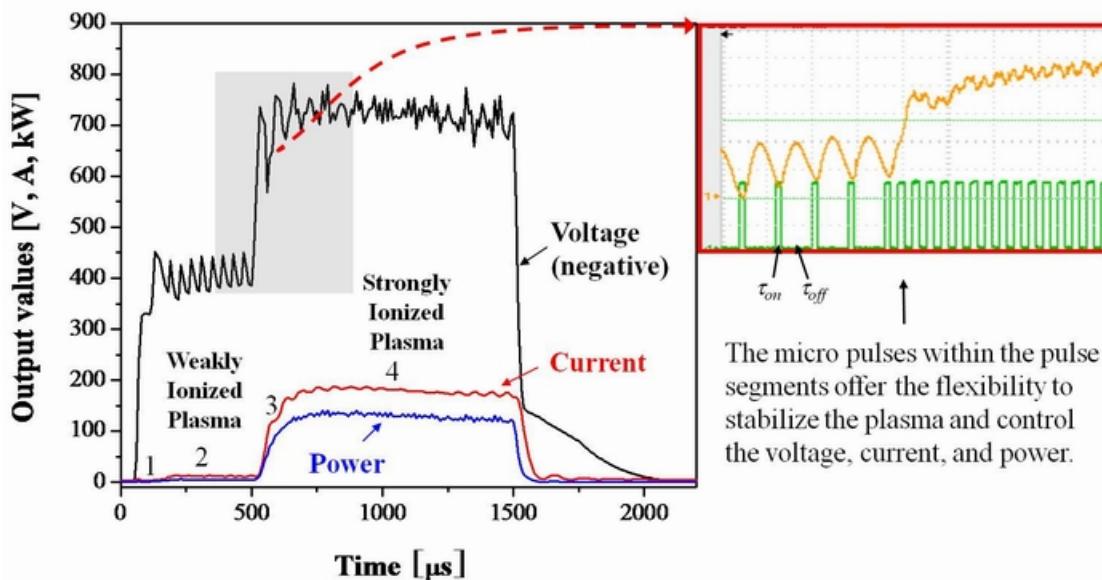
also known as HPPMS (High Power Pulse Magnetron sputtering)

Pulse with a **power density** at the target surface during the pulse exceeding the typical dc power density by about **two orders of magnitude**. This implies that the **off-time between pulses is long**, and the **duty cycle is only of order 1%**.

20 eV - 100 eV (vs. only about 2 -10 eV in conventional sputtering).

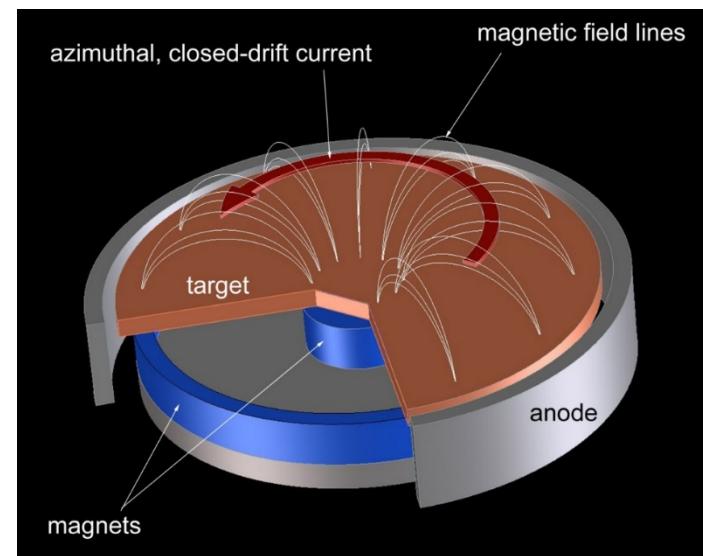


*Variation: Burst HiPIMS or Modulated Pulse Power (MPP)*



Increase High rate deposition

Magnetron as an Electron Trap



# Ionization Zones

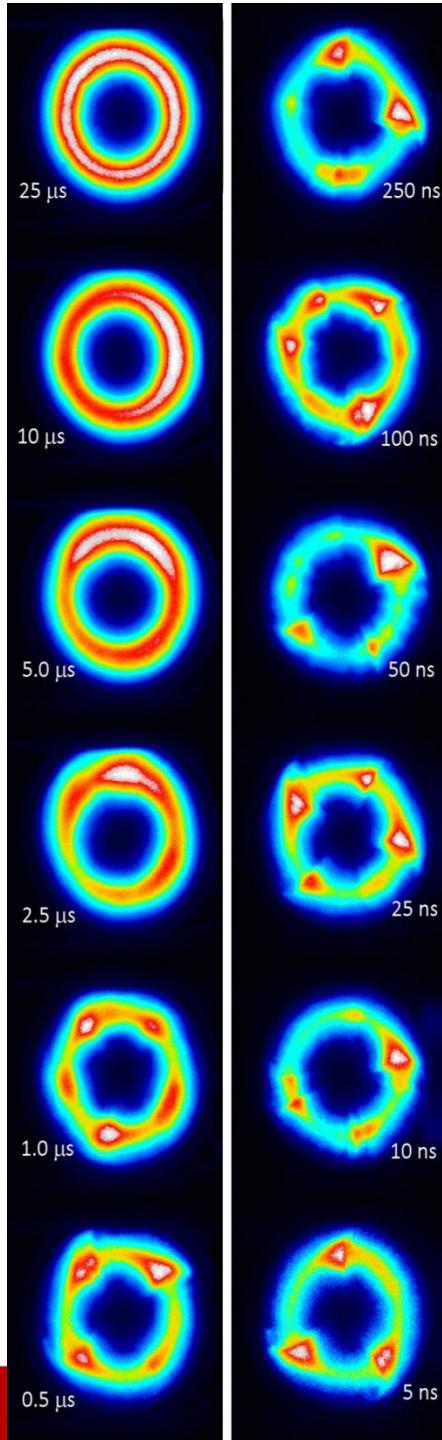
The HiPIMS plasma breaks down in isolated ionization zones (IZs) that rotate in the direction given by the ExB drift, with velocities around  $10^4$  ms<sup>-1</sup> and frequencies in the range of about 100 kHz.

- Positive feedback loop between electron mean free path and ionization leads to “bunching” of plasma in **ionization zones**
- Ionization zones move in ExB direction because ions are “evacuated” from ionization zones by electric field, exposing new neutrals to ionization by drifting electrons
- Electrons drift according to the local E and B fields, perpendicular to both, and produce electron jets related to the azimuthal electric field of the plasma zone
- the physically relevant power density of HIPIMS is much higher than the typically reported average power density
- **Ionization zones explain why HIPIMS works as observed, and offer “energetic condensation” in the context of sputtering and SRF coatings.**

From the target point of view, a HiPIMS discharge represents therefore a situation of continuous temporal and spatial change in local sputtering conditions.

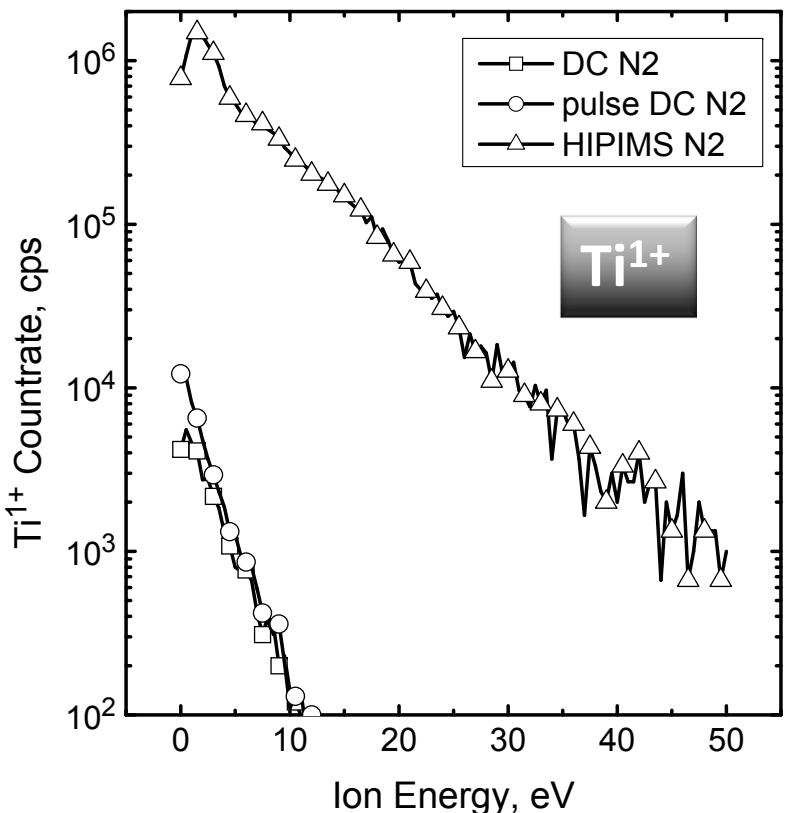
- 3" Nb target, peak current ~ 200 A
- reduction of image exposure time gives immediate clues on rotational speed → ~  $10^4$  m/s

A. Anders *et al.*, J. Appl. Phys. 111 (2012) 053304



# HiPIMS – Applications to SRF Surfaces

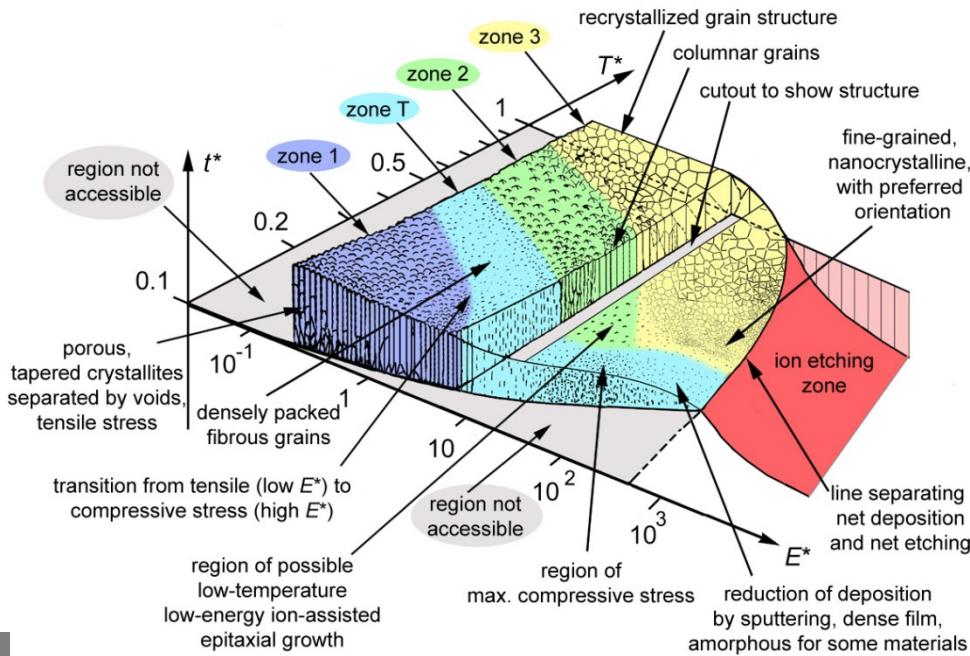
## Ion Energy Distribution Function



A. P. Ehiasarian, *et al.*, Plasma Processes and Polymers 4 (2007) S309

Enhanced power density is the key to the desired ionization of sputtered material: films are denser, smoother, and some grain texture control is possible.

## “Structure Zone Diagram”

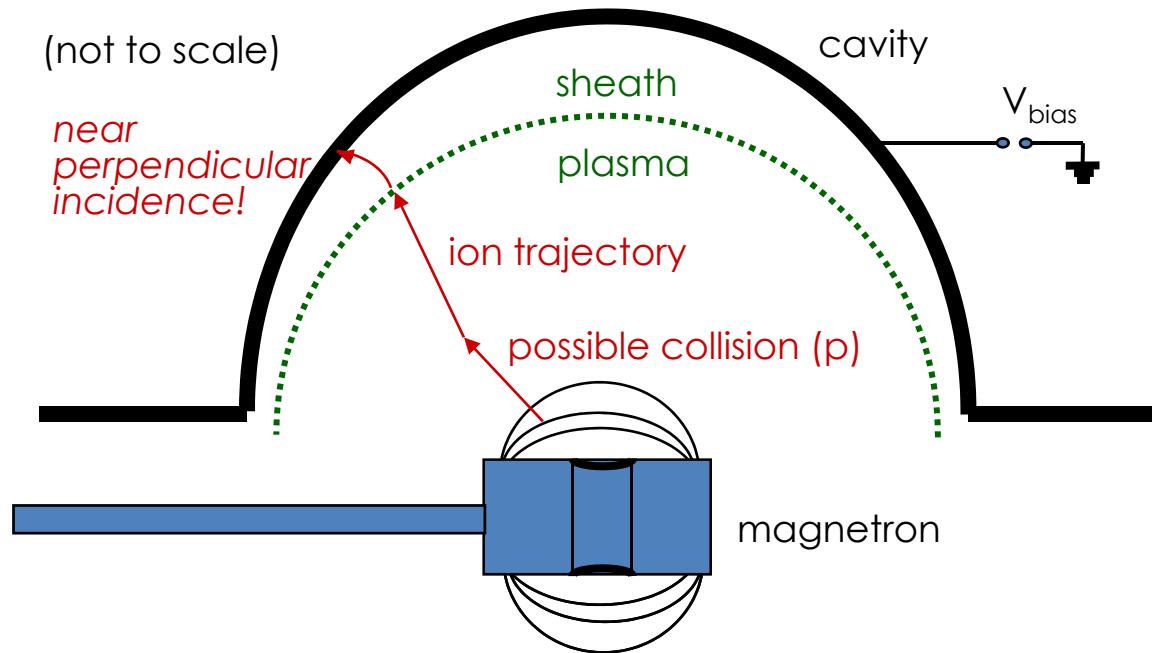


A. Anders, Thin Solid Films 518 (2010) 4087.

# HiPIMS – Applications to SRF Surfaces

## Bias voltage:

Control ion trajectories & energy in collisionless sheath



## In-situ substrate pre-treatment:

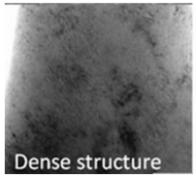
Cleaning or oxide layer removal – typically with plasma etching (high voltage applied to the substrate)

Interface engineering - film forming species are implanted in the substrate, forming a gradient towards the surface

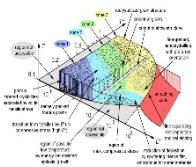
# HiPIMS – Applications to SRF Surfaces



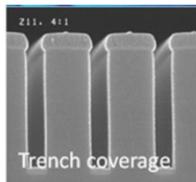
High level of ionization  
High energy ions, tunable with bias voltages



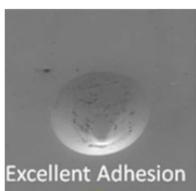
Film densification  
Film smoothness



Possibility to control the film structure



Good surface coverage (even for high aspect ratio objects)



Enhanced adhesion to substrate

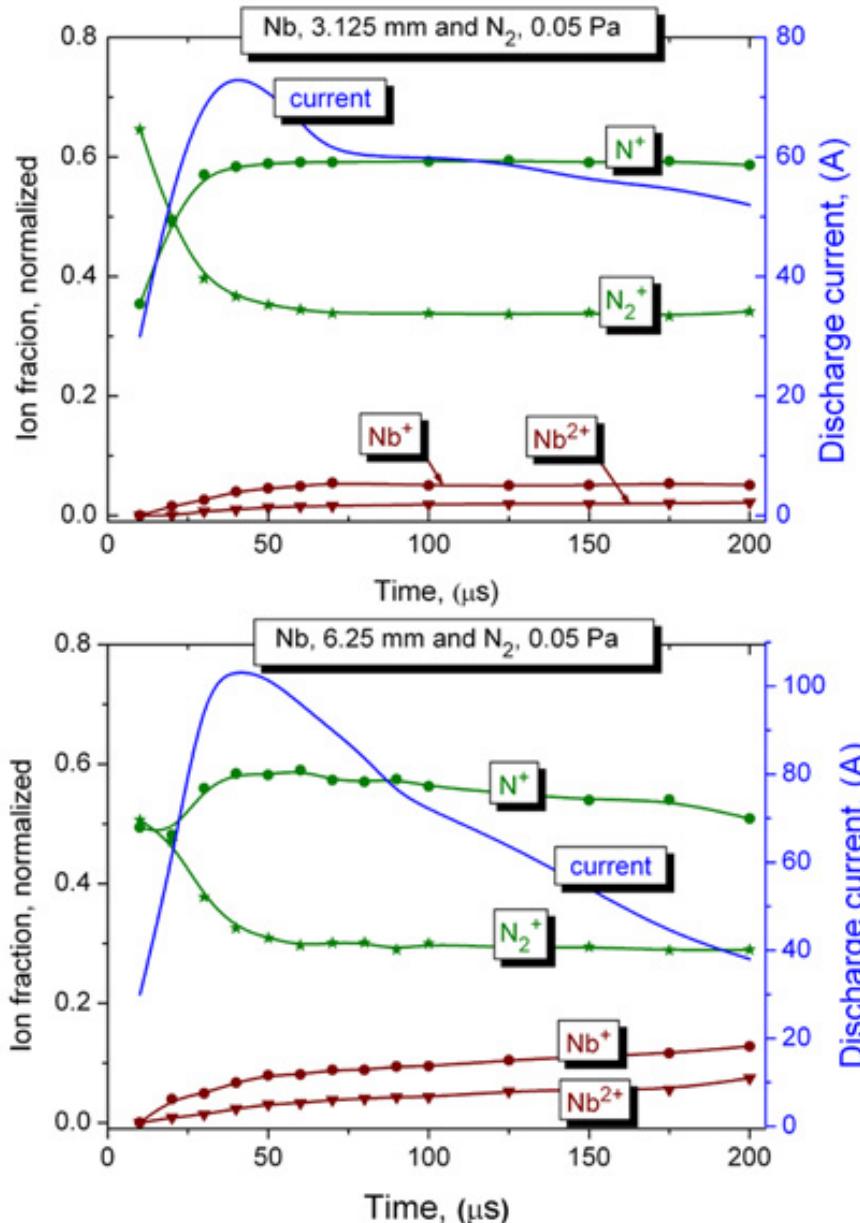
# HiPIMS – Applications to SRF Surfaces

## Easy extension to other materials

- ❑ Relatively straight forward to produce NbN, NbTiN & multilayers
- ❑ Possibility to use two different cathode materials with two asymmetrically operating magnetrons to produce Nb<sub>3</sub>Sn, MgB<sub>2</sub>, ...

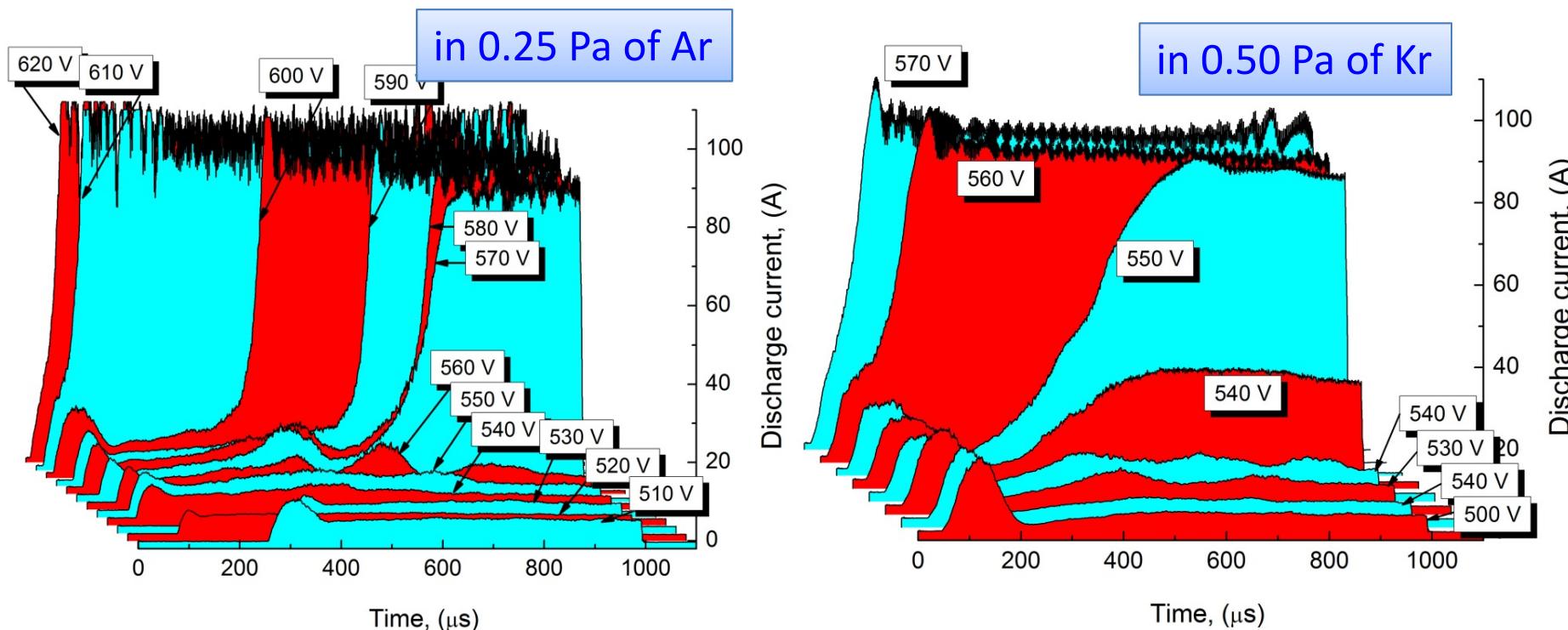
Preliminary TOF study of Nb HiPIMS with N<sub>2</sub> gas: the measured ion species promise the formation of dense, textured NbN

A. Anders and Yu. Yushkov, J. Appl. Phys. **105**  
(2009) 073301



# HiPIMS – LBNL

*Plasma Studies especially for Nb*



A. Anders, Surf. Coat. Technol. **205** (2011) S1.

## HIPIMS and Self-Sputtering of Niobium

HIPIMS with Nb target , Ø 5 cm

# HiPIMS – LBNL

3 regimes in the HiPIMS discharge

Regime I: Low voltage (<550V), high impedance

Regime II: Mid voltage (550<V<650), low impedance

Regime III: High voltage (>650 V) high impedance

*Plasma Studies especially for Nb*

R. Mendlesberg, A. Anders

**Superimpose a Mid Frequency (MF) discharge in between the HiPIMS pulses to lower frequency the HiPIMS pulses**

**HiPIMS pulses do not depend on MF pulse pattern**

**As long as the MF discharge is there, the HiPIMS pulses can be spaced as far (or close) in time as desired.**

**HiPIMS pulses must be longer than 50  $\mu$ s**

**Relative power in HiPIMS and MF components is tunable**

**Nb<sup>+</sup> emission lines dominate the emission spectrum starting at moderate voltages**

**Intensity of all lines increases with increasing discharge voltage**

**OES peak ratios give some information on changes in relative density of each ionic species**

**For film growth, applied voltage should be about 650V**

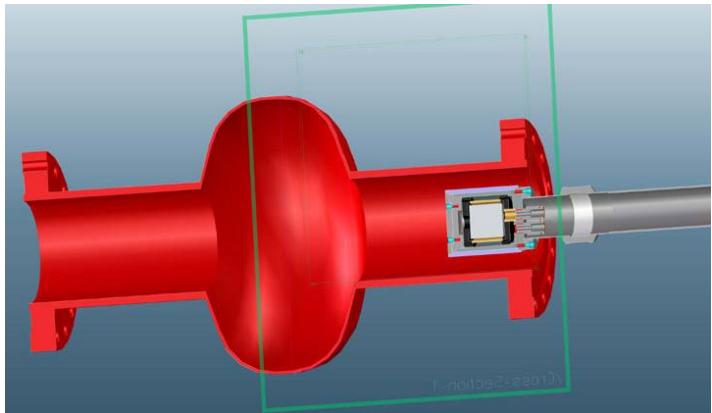
discharge right in the low voltage end of Regime III for pulse widths greater than 100  $\mu$ s

Large population of Nb<sup>+</sup> at this voltage, Creation of Nb<sup>2+</sup>, which doesn't aid film growth and more than Nb<sup>+</sup>, is minimized

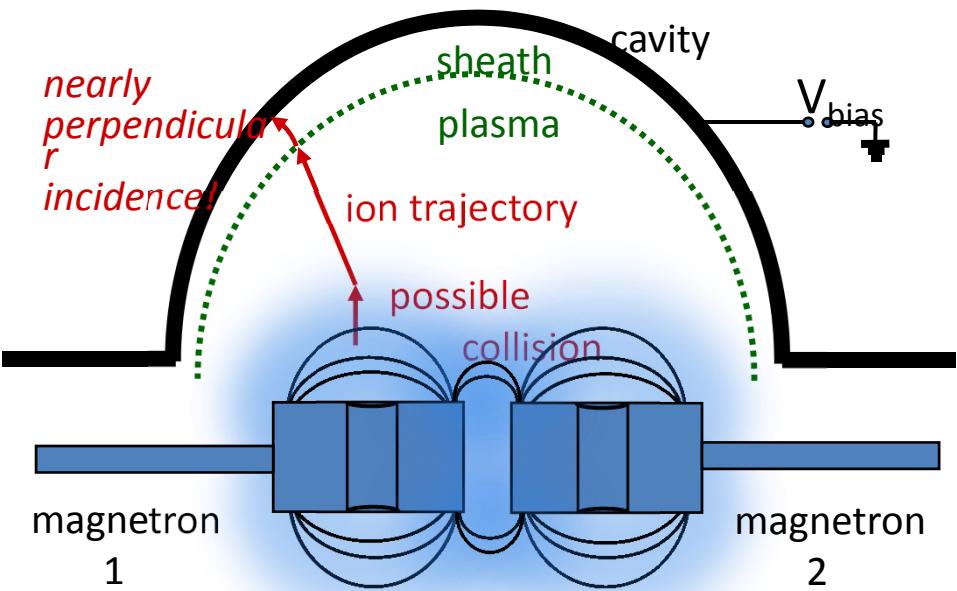
Moderate voltage will reduce tendency for arcing

# HiPIMS – LBNL

(collaboration with ANL, JLab)



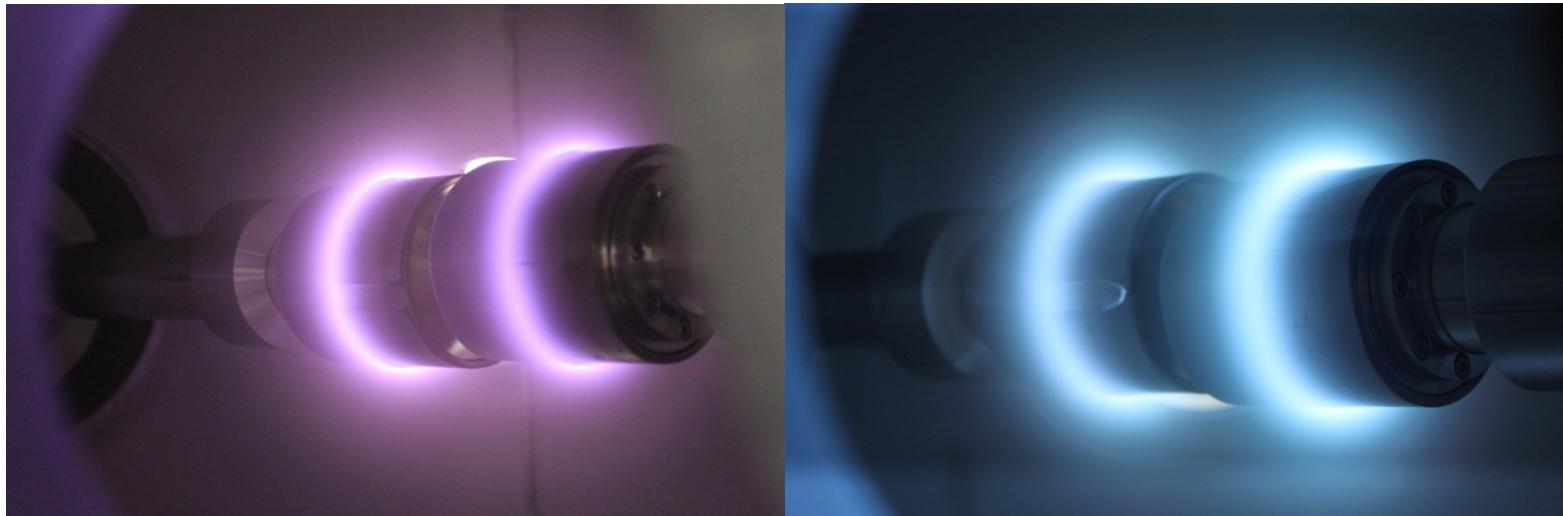
Dedicated Nb-HIPIMS Chamber



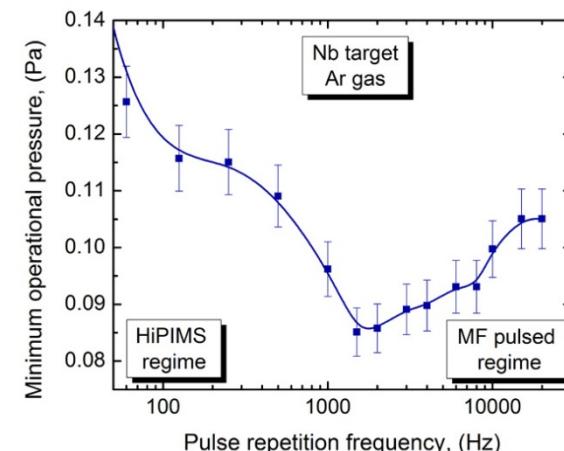
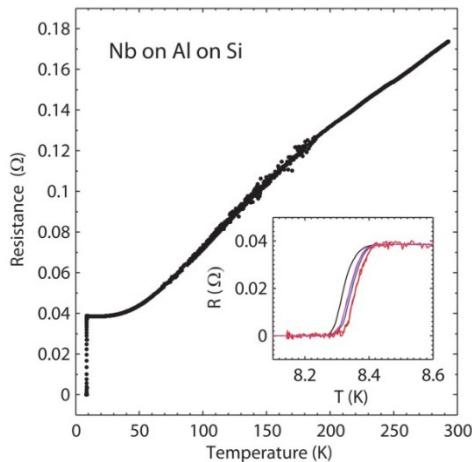
Dual Magnetron: Most effective for a Biasing & influencing Ion Energies and Trajectories

- chamber for 1.3 GHz SRF cavities
- base pressure in the low  $10^{-8}$  range
- residual gas analyzer
- 2 small cylindrical, movable magnetrons
- decoupled substrate heating and biasing
- pyrometer 100-600 °C
- 2 SIPP pulsers for dual-HIPIMS and bias

# HIPIMS -LBNL



- dual cylindrical magnetron in at relatively low power sputtering mode
- Dominated by argon emission
- dual cylindrical magnetron in high power mode (above runaway threshold)
- Dominated by niobium emission



# HiPIMS – CERN

## *Collaboration with Sheffield Hallam University*

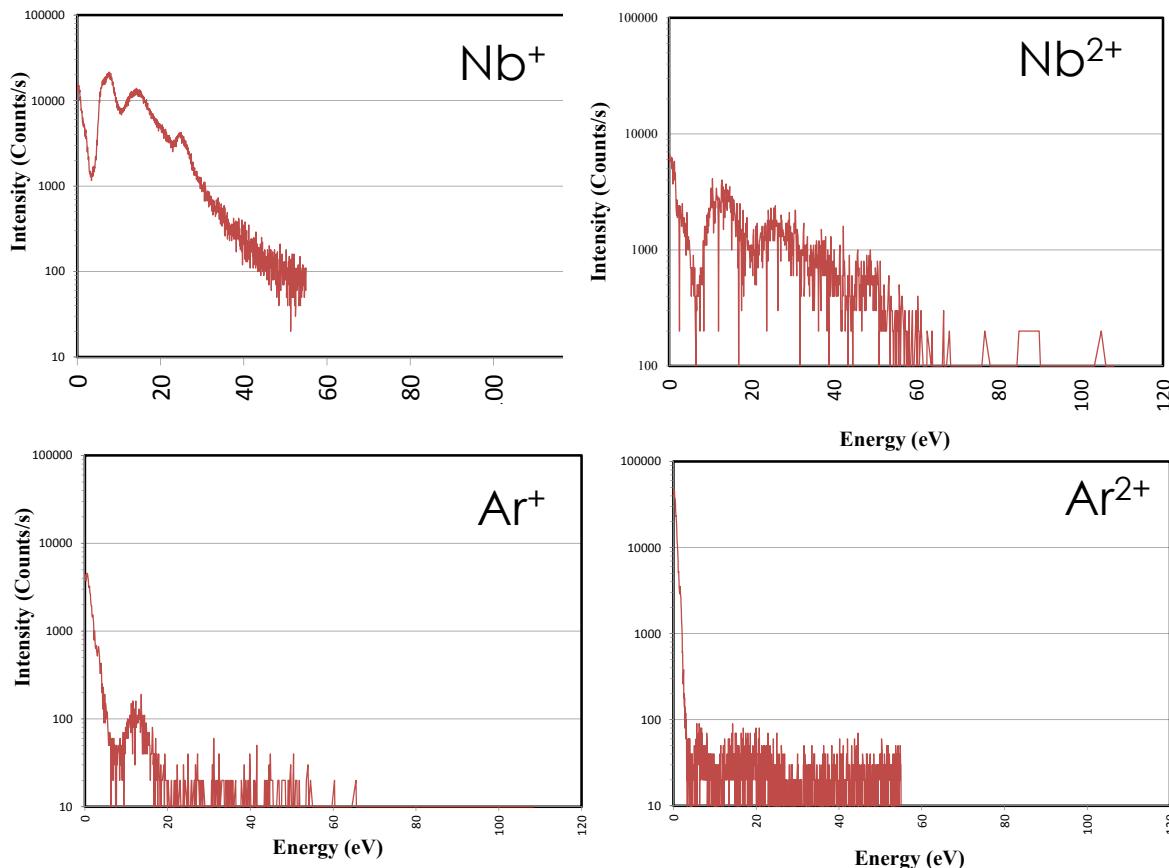
Sheffield Hallam University:

Plasma Studies

CERN:

1.3-1.5 GHz cavity deposition

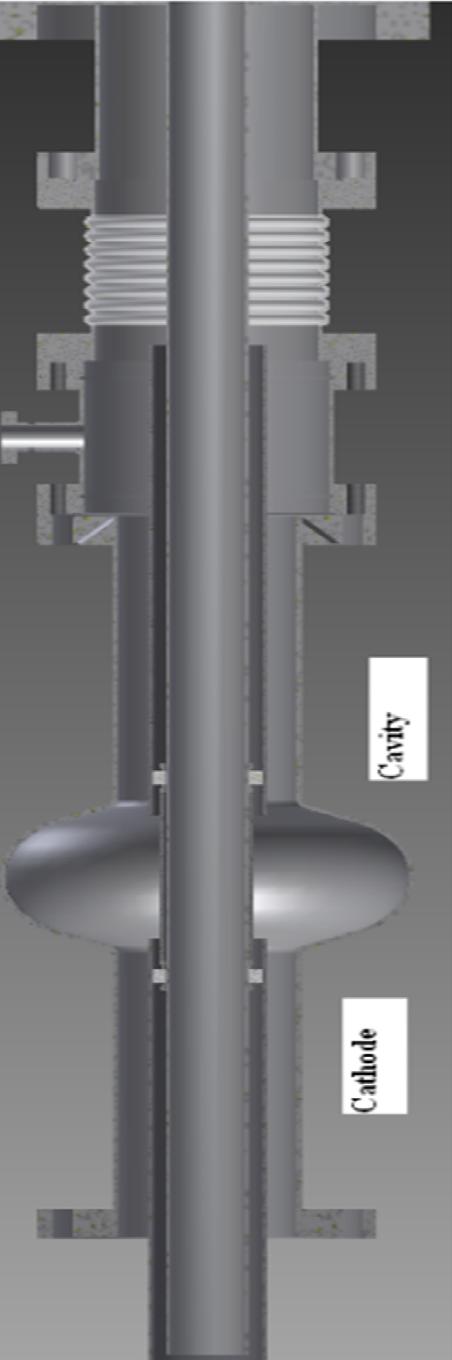
Ion Energy Dispersion Function  
(IEDF)



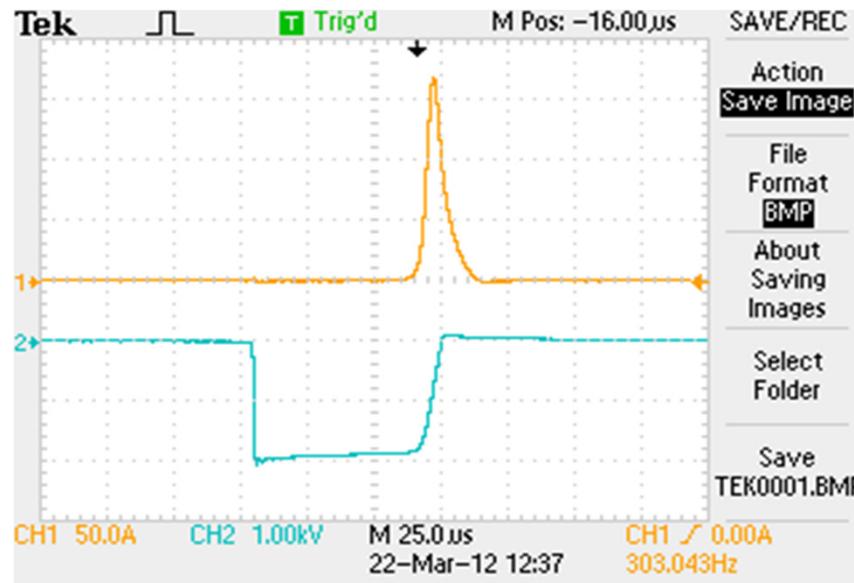
G. TERENZIANI, S. CALATRONI, A.P. EHIASARIAN, NB  
COATINGS FOR SUPERCONDUCTING RF APPLICATIONS  
BY HIPIMS, 2013-09-11



# HiPIMS – CERN



Vertical cylindrical magnetron  
Base pressure  $10^{-10} - 10^{-11}$  mbar  
Movable SmCo magnet

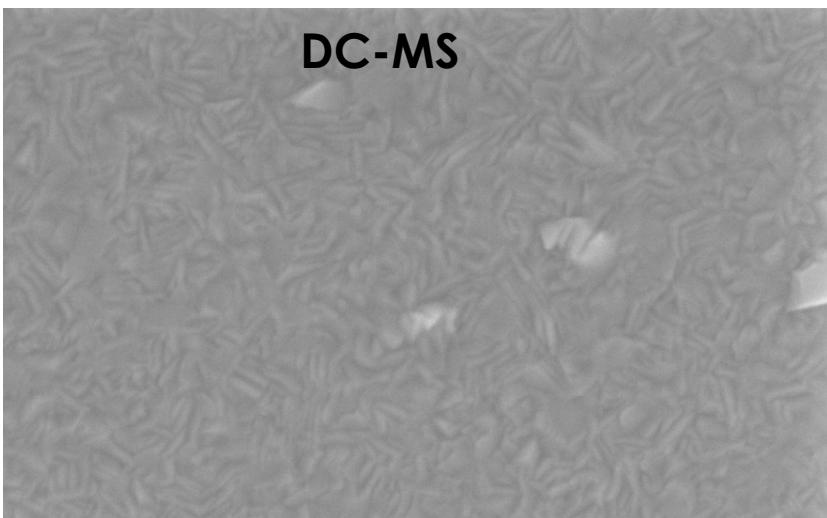


Typical HiPIMS current and voltage behavior

Hüttinger Electronics TruPlasma Highpulse DC Unit:  
10 kW max average power delivered  
voltage up to 2 kV  
pulse width up to 200 us  
frequency up to 500 Hz.

# HiPIMS – CERN

DC-MS



100 nm



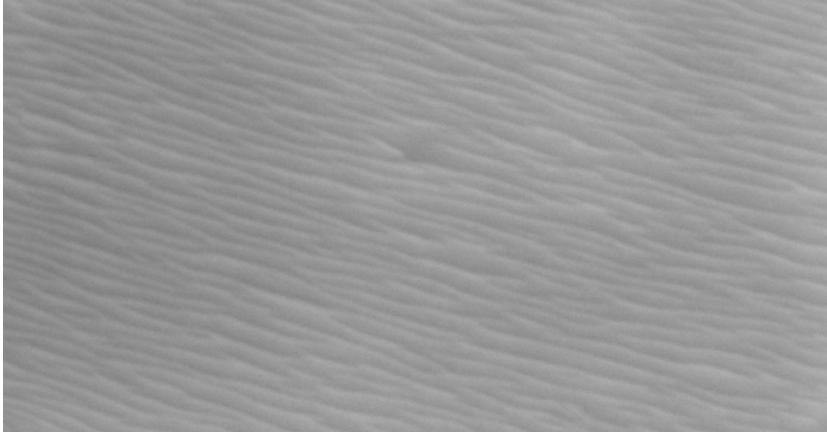
EHT = 5.00 kV  
WD = 0.9 mm

Nb coating on Cu  
DCMS

Mag = 50.00 K X  
Ignacio Aviles



HIPIMS /150 A peak current



200 nm



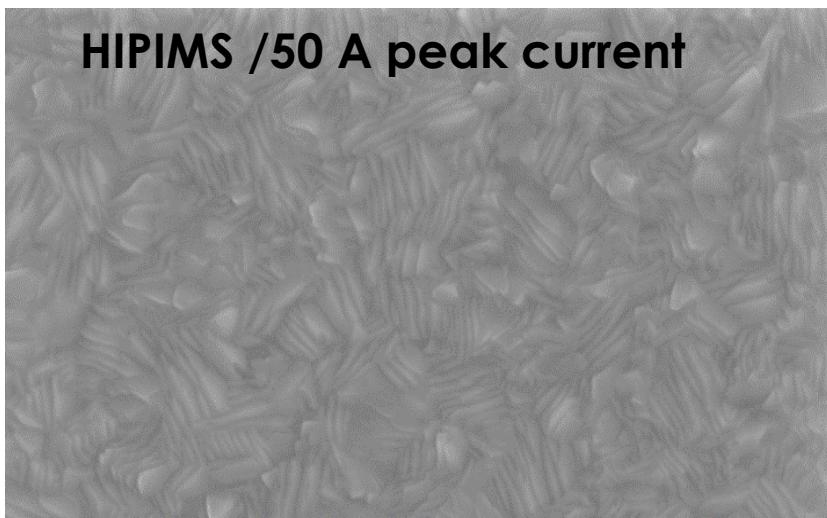
EHT = 10.00 kV  
WD = 1.0 mm  
Signal A = InLens

HIE-ISOLDE  
HiPIMS Nb coating on Cu  
Holder 1

Mag = 50.00 K X  
Ignacio Aviles  
Date : 8 Feb 2012



HIPIMS /50 A peak current



100 nm



EHT = 10.00 kV  
WD = 1.3 mm

HIE-ISOLDE  
HIPIMS Nb coating on Cu

Mag = 50.00 K X  
Maud Scheubel



HIPIMS /200 A peak current

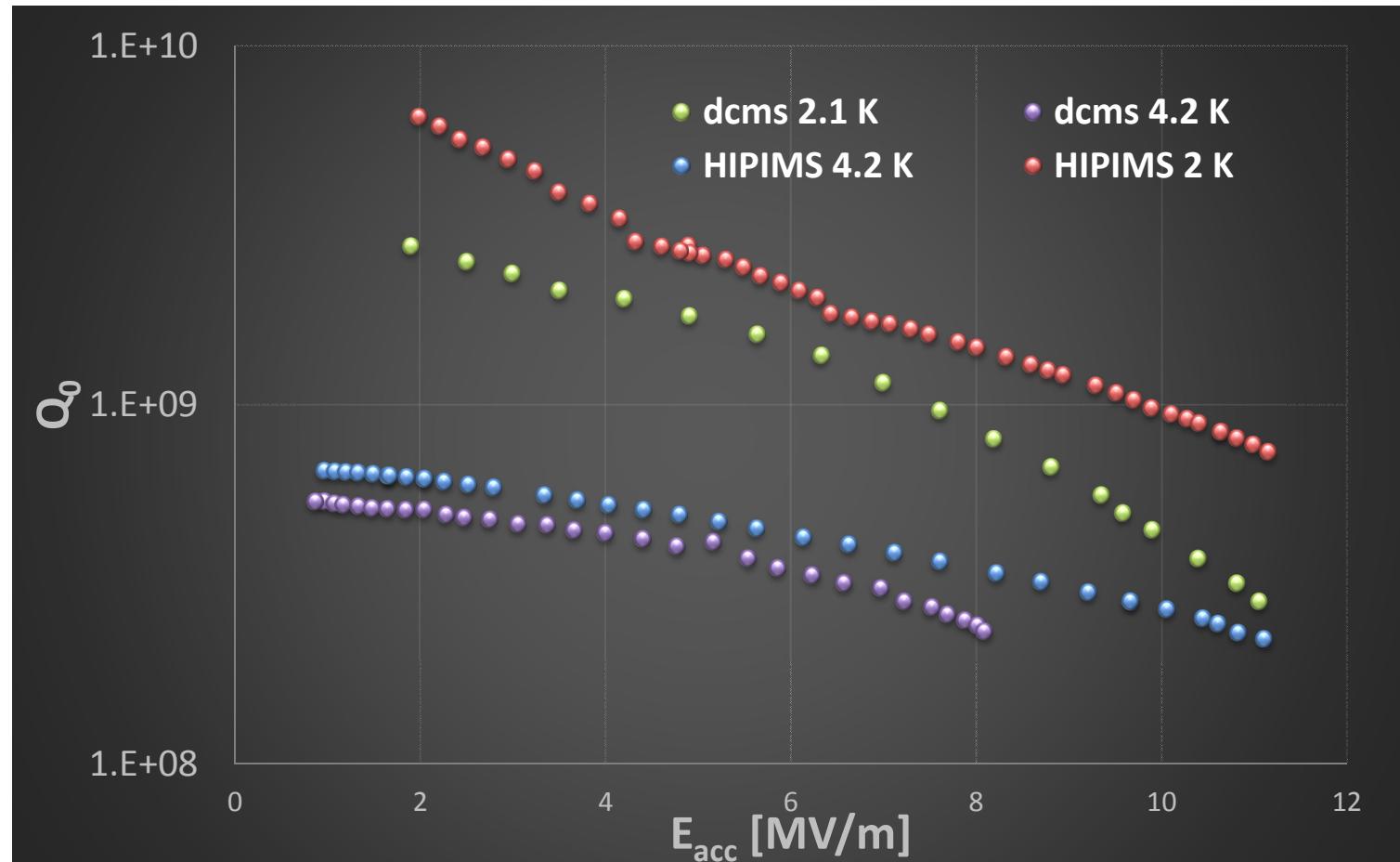


spot WD HV det Lens Mode mode mag 500 nm  
3.5 4.4 mm 13.50 kV TLD Immersion SE 140 065 x

# HiPIMS – CERN

Nb/Cu cavities have been produced both by DC cylindrical magnetron sputtering and cylindrical HiPIMS with Kr

peak current 200 A  
( $2 \text{ A/cm}^2$ )  
 $\Delta V = 570 \pm 10 \text{ V}$   
Average current  
2.6 A  
Pulse width 200  $\mu\text{s}$   
frequency 106 Hz.

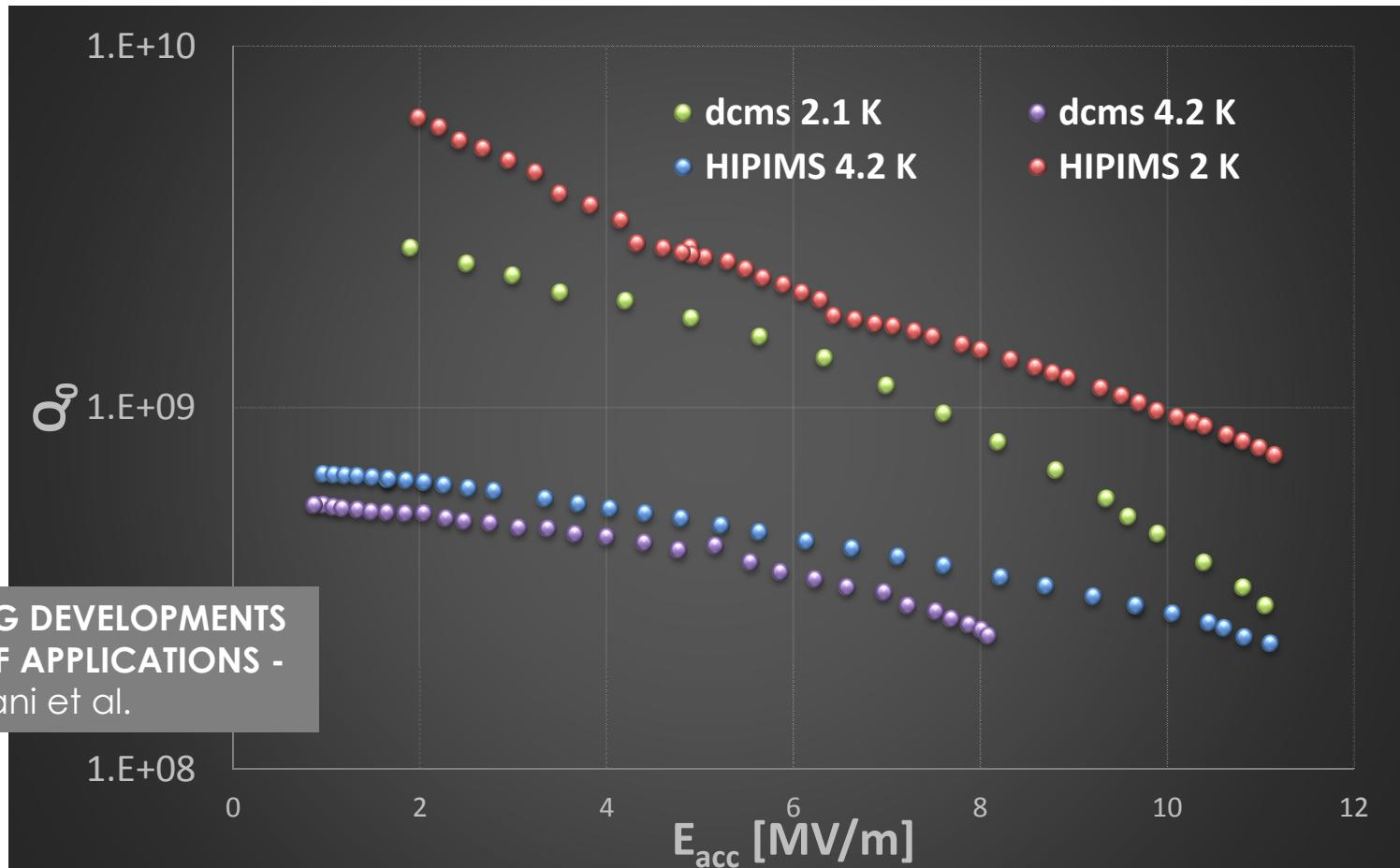


**Note:** - Substrate preparation is SUBU (by opposition to electropolishing for the best 1.5GHz DCMS Nb/Cu cavities to date)  
- Measurement at higher fields than 11MV/m prevented by interlock system due to radiation

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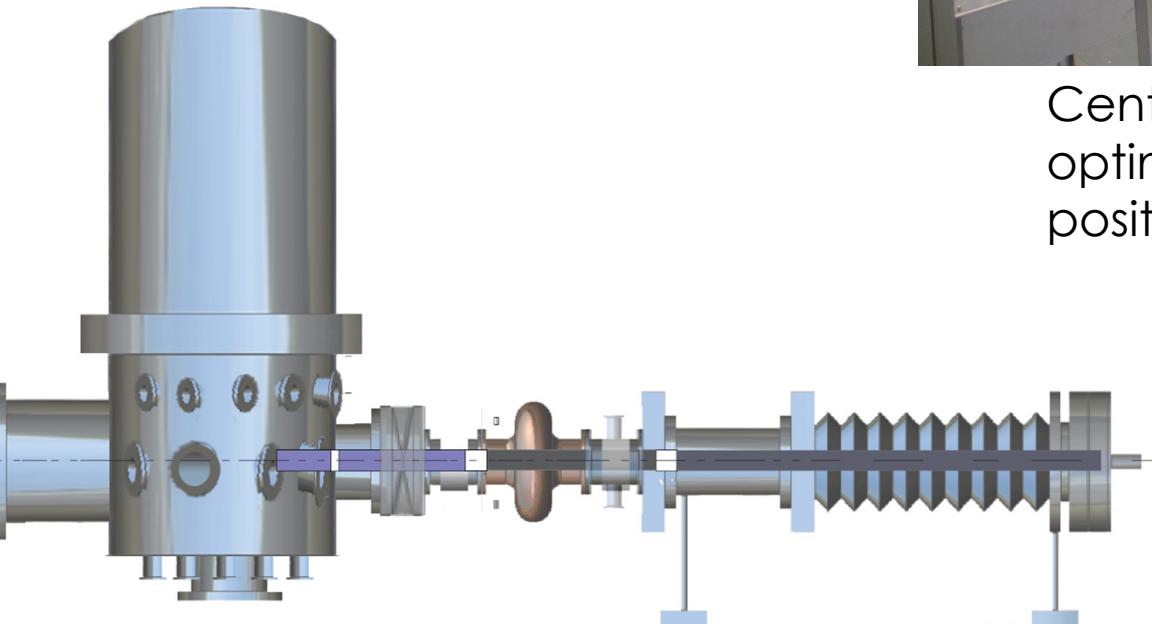
# HiPIMS – JLab

## *Collaboration with LBNL, College William & Mary*

Study on samples & cavities

2 coating systems:

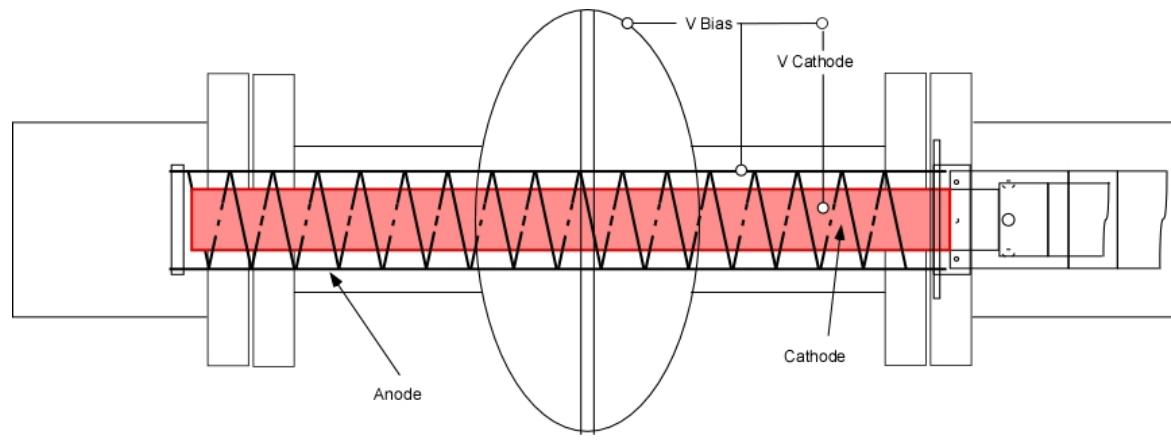
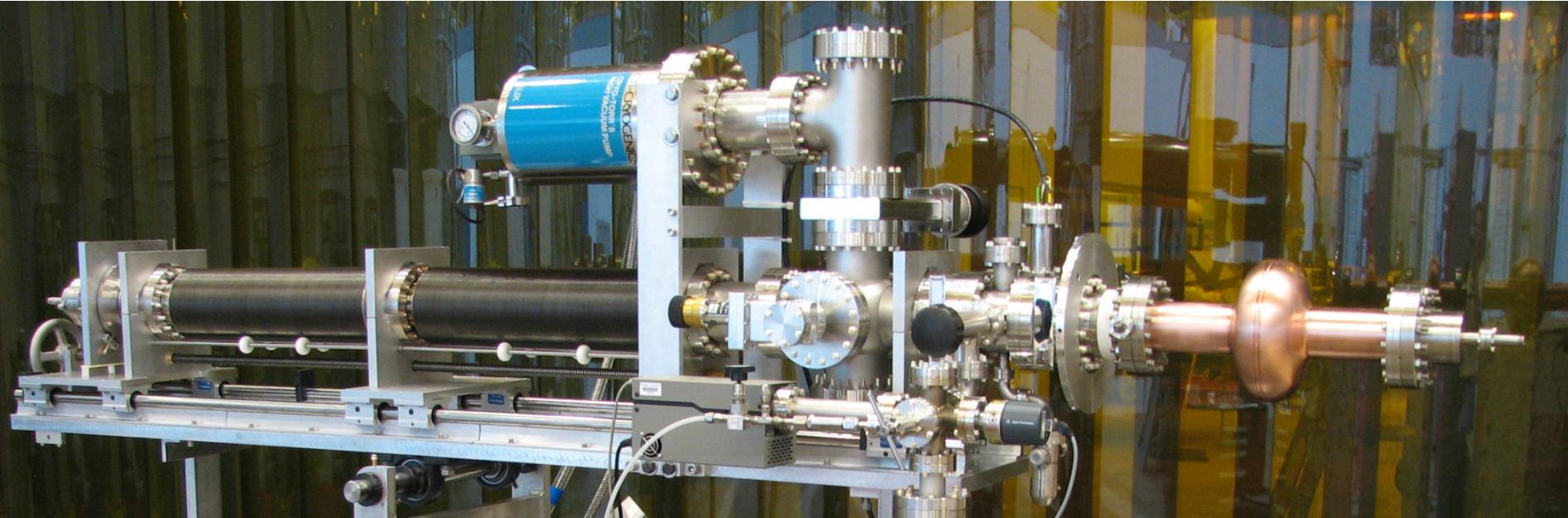
- UHV Multi-technique Deposition system**
- Cylindrical HiPIMS cavity system**



Center stage in development to optimize the sample-target relative positions for Nb and Multilayer films

**Bridge studies with energetic condensation Nb films produced by ECR ( $Nb^+$  ions in UHV)**

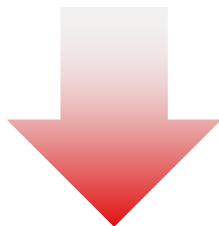
# HiPIMS – JLab



- ❑ Niobium cathode
- ❑ Open grid-like Nb anode
- ❑ internal rare earth magnets with field extending entire cathode & cavity length
- ❑ Penetrating cathode every 1.7 cm producing a peak B field of 0.2 T at a 4 mm distance from the cathode surface with the same longitudinal periodicity.
- ❑ Water cooled

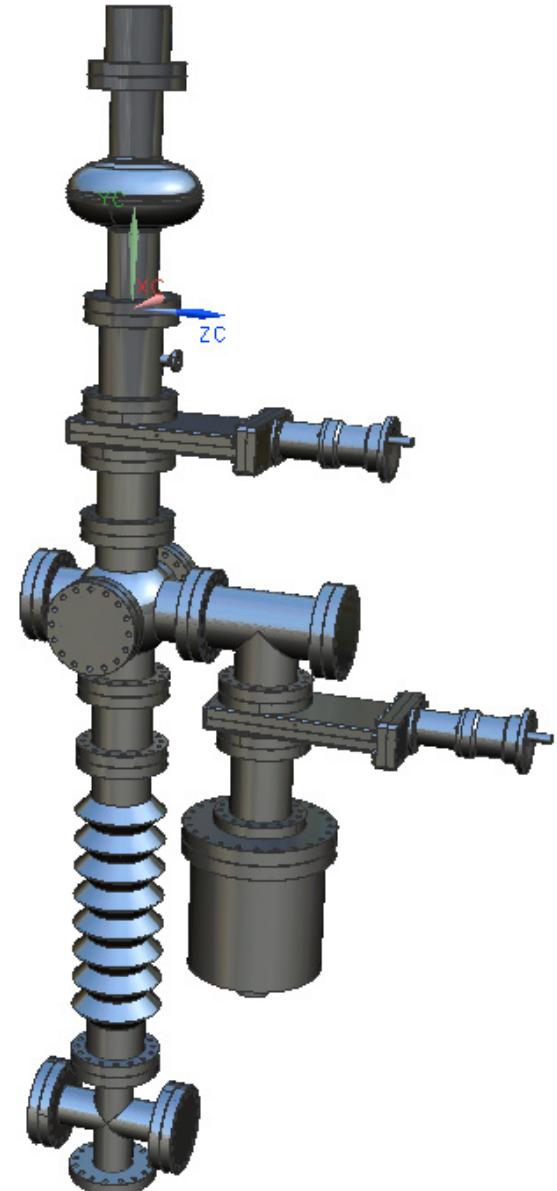
# HiPIMS – JLab

- Ion flux characterization under various pulse conditions
- Ion energy spectrum & Nb ions to neutral ratio. (several anode designs)
- System parameter space & film properties (initially  $T_c$  & RRR)



## Cavity coating procedure:

- Substrate preparation: CBP + Electropolishing
- Assembly in clean room
- Pump down and bake-out to adequate temperature
- Coating parameters derived from work done with ECR plasma
- Coating with Kr: less trapped in the niobium film, tends to damp plasma instabilities than argon



# Conclusions

- ❑ HiPIMS is an emerging array of energetic condensation techniques with extensive studies in plasma physics and materials
- ❑ HIPIMS has the advantage of not generating macroparticles (assuming that arcing is prevented)
- ❑ Nb has a relatively low self-sputtering yield → “gasless” self-sputtering in vacuum could not be demonstrated
- ❑ low pressure operation works well with optimized pulse frequency.
- ❑ HIPIMS cavity systems are ready in the Laboratories involved with HiPIMS.
- ❑ Nb/Cu cavities have already been coated at CERN with encouraging results.
- ❑ Technique directly applicable to material systems beyond Nb.

